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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	200
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	70
Number of Gates	1500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1415a-1plg84m

Ordering Information

A14100 A – 1 RQ G 208 C

- C: Application (Temperature Range)
  - C = Commercial (0 to +70°C)
  - I = Industrial (–40 to +85°C)
  - M = Military (–55 to +125°C)
  - B = MIL-STD-883
- 208: Package Lead Count
- G: Lead-Free Packaging
  - Blank = Standard Packaging
  - G = RoHS Compliant Packaging
- RQ: Package Type
  - PG = Ceramic Pin Grid Array
  - PL = Plastic Leaded Chip Carrier
  - PQ = Plastic Quad Flatpack
  - RQ = Plastic Power Quad Flatpack
  - VQ = Very Thin (1.0 mm) Quad Flatpack
  - TQ = Thin (1.4 mm) Quad Flatpack
  - CQ = Ceramic Quad Flatpack
  - BG = Plastic Ball Grid Array
- 1: Speed Grade
  - Std = Standard Speed
  - –1 = Approximately 15% faster than Standard
  - –2 = Approximately 25% faster than Standard
  - –3 = Approximately 35% faster than Standard
- A: Die Revision
  - A = 1.0 mm CMOS Process
- A14100: Part Number
  - A1415A = 1,500 Gates
  - A14V15A = 1,500 Gates (3.3 V)
  - A1425A = 2,500 Gates
  - A14V25A = 2,500 Gates (3.3 V)
  - A1440A = 4,000 Gates
  - A14V40A = 4,000 Gates (3.3 V)
  - A1460A = 6,000 Gates
  - A14V60A = 6,000 Gates (3.3 V)
  - A14100A = 10,000 Gates
  - A14V100A = 10,000 Gates (3.3 V)

Notes:

1. *The –2 and –3 speed grades have been discontinued.*
2. *The Ceramic Pin Grid Array packages PG100, PG133, and PG175 have been discontinued in all device densities, speed grades, and temperature grades.*
3. *The Plastic Ball Grid Array package BG225 has been discontinued in all device densities (specifically for A1460A), all speed grades, and all temperature grades.*
4. *Military Grade devices are no longer available for the A1440A device.*
5. *For more information about discontinued devices, refer to the Product Discontinuation Notices (PDNs) listed below, available on the Microsemi SoC Products Group website:*
   PDN March 2001
   PDN 0104
   PDN 0203
   PDN 0604
   PDN 1004

Device/Package	Speed Grade[1]				Application[1]			
	Std.	–1	–2	–3	C	I	M	B
A14V40A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
A1460A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–
196-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
207-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
208-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
225-Pin Plastic Ball Grid Array (BGA)	D	D	D	D	D	–	–	–
A14V60A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
208-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A14100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	✓	D	D	✓	✓	–	–
257-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
313-Pin Plastic Ball Grid Array (BGA)	✓	✓	D	D	✓	–	–	–
256-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
A14V100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	–	–	–	✓	–	–	–
313-Pin Plastic Ball Grid Array (BGA)	✓	–	–	–	✓	–	–	–

Notes:

1. *Applications:*
   C = Commercial
   I = Industrial
   M = Military
2. *Commercial only*

Availability:
✓ = Available
P = Planned
– = Not planned
D = Discontinued

Speed Grade:
–1 = Approx. 15% faster than Std.
–2 = Approx. 25% faster than Std.
–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

Microsemi

1 – ACT 3 Family Overview

General Description

Microsemi's ACT 3 Accelerator Series of FPGAs offers the industry's fastest high-capacity programmable logic device. ACT 3 FPGAs offer a high performance, PCI compliant programmable solution capable of 186 MHz on-chip performance and 9.0 nanosecond clock-to-output (–1 speed grade), with capacities spanning from 1,500 to 10,000 gate array equivalent gates.

The ACT 3 family builds on the proven two-module architecture consisting of combinatorial and sequential logic modules used in Microsemi's 3200DX and 1200XL families. In addition, the ACT 3 I/O modules contain registers which deliver 9.0 nanosecond clock-to-out times (–1 speed grade). The devices contain four clock distribution networks, including dedicated array and I/O clocks, supporting very fast synchronous and asynchronous designs. In addition, routed clocks can be used to drive high fanout signals such as flip-flop resets and output.

The ACT 3 family is supported by Microsemi's Designer Series Development System which offers automatic placement and routing (with automatic or fixed pin assignments), static timing analysis, user programming, and debug and diagnostic probe capabilities.

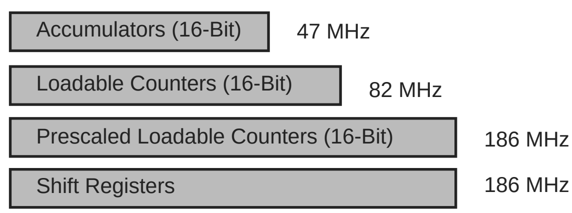
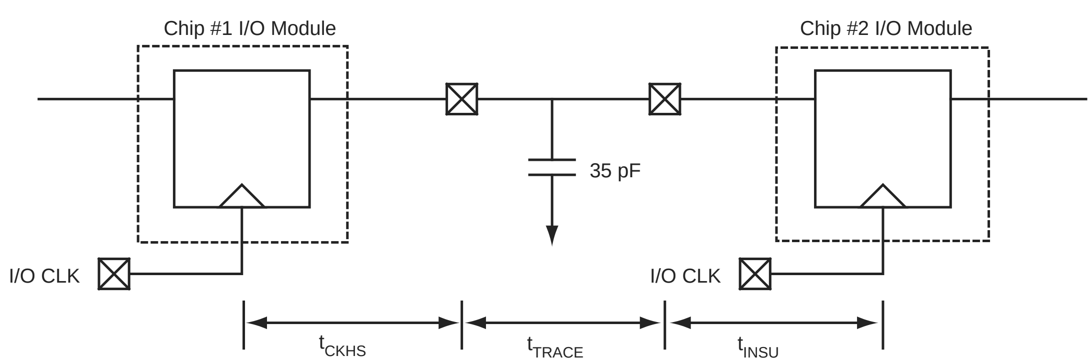


Figure 1-1 • **Predictable Performance (worst-case commercial, –1 speed grade)**

System Performance Model



The S-module contains a full implementation of the C-module plus a clearable sequential element that can either implement a latch or flip-flop function. The S-module can therefore implement any function implemented by the C-module. This allows complex combinatorial-sequential functions to be implemented with no delay penalty. The Designer Series Development System will automatically combine any C-module macro driving an S-module macro into the S-module, thereby freeing up a logic module and eliminating a module delay.

The clear input CLR is accessible from the routing channel. In addition, the clock input may be connected to one of three clock networks: CLKA, CLKB, or HCLK. The C-module and S-module functional descriptions are shown in Figure 2-2 and Figure 2-3 on page 2-2. The clock selection is determined by a multiplexer select at the clock input to the S-module.

I/Os

I/O Modules

I/O modules provide an interface between the array and the I/O Pad Drivers. I/O modules are located in the array and access the routing channels in a similar fashion to logic modules. The I/O module schematic is shown in Figure 4. The signals DataIn and DataOut connect to the I/O pad driver.

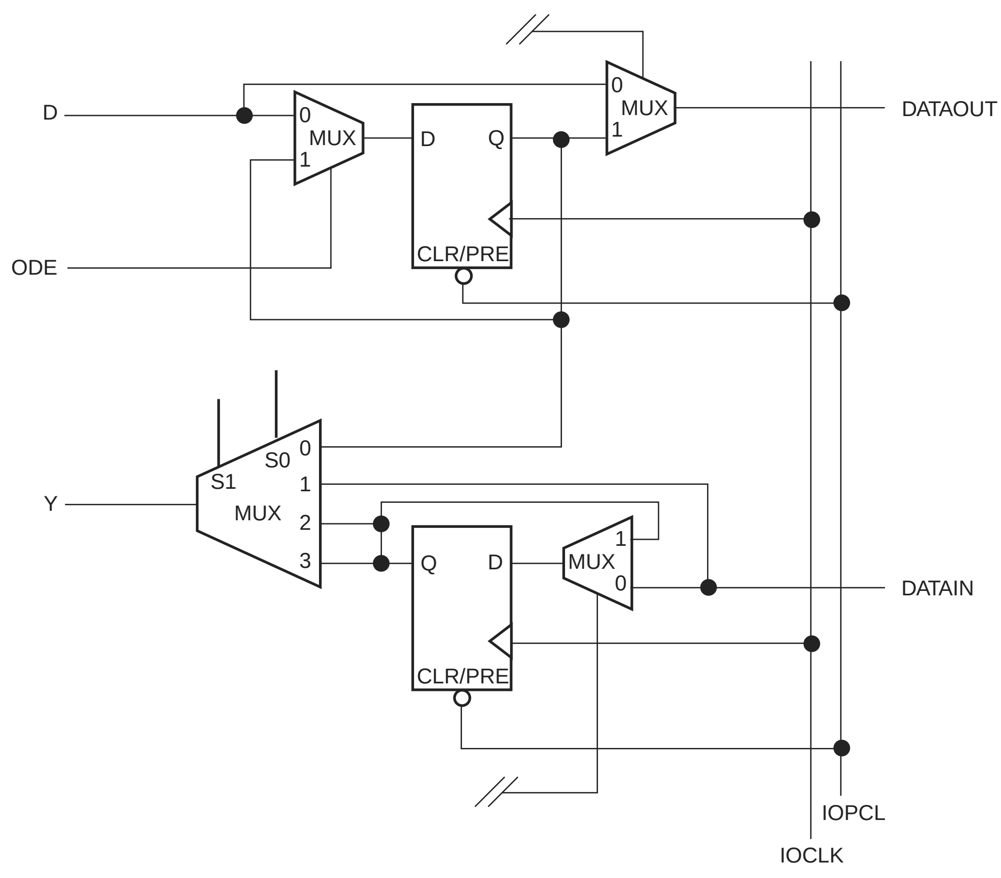


Figure 2-4 • **Functional Diagram for I/O Module**

Each I/O module contains two D-type flip-flops. Each flip-flop is connected to the dedicated I/O clock (IOCLK). Each flip-flop can be bypassed by nonsequential I/Os. In addition, each flip-flop contains a data enable input that can be accessed from the routing channels (ODE and IDE). The asynchronous preset/clear input is driven by the dedicated preset/clear network (IOPCL). Either preset or clear can be selected individually on an I/O module by I/O module basis.

3.3 V Operating Conditions

Table 2-5 • **Absolute Maximum Ratings[1], Free Air Temperature Range**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current[2]	±20	mA
T_{STG}	Storage temperature	–65 to +150	°C

Notes:

1. *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.*
2. *Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.*

Table 2-6 • **Recommended Operating Conditions**

Parameter	Commercial	Units
Temperature range*	0 to +70	°C
Power supply tolerance	3.0 to 3.6	V

*Note: *Ambient temperature (T_A) is used for commercial.*

Table 2-7 • **Electrical Specifications**

Parameter		Commercial Min.	Commercial Max.	Units
VOH[1]	IOH = –4 mA	2.15	–	V
	IOH = –3.2 mA	2.4		V
VOL[1]	IOL = 6 mA		0.4	V
VIL		–0.3	0.8	V
VIH		2.0	VCC + 0.3	V
Input transition time t_R, t_F[2]	VI = VCC or GND	–10	+10	µA
C_{IO} I/O Capacitance[2,3]			10	pF
Standby current, ICC[4] (typical = 0.3 mA)			0.75	mA
Leakage current[5]		–10	10	µA

1. *Only one output tested at a time. VCC = minimum.*
2. *Not tested; for information only.*
3. *Includes worst-case 84-pin PLCC package capacitance. VOUT = 0 V, f - 1 MHz.*
4. *Typical standby current = 0.3 mA. All outputs unloaded. All inputs = VCC or GND.*
5. *VO, VIN = VCC or GND*

Equivalent capacitance is calculated by measuring ICC active at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency independent so that the results may be used over a wide range of operating conditions. Equivalent capacitance values are shown in Figure 2-10.

Table 2-10 **• CEQ Values for Microsemi FPGAs**

Item	CEQ Value
Modules (C_{EQM})	6.7
Input Buffers (C_{EQI})	7.2
Output Buffers (C_{EQO})	10.4
Routed Array Clock Buffer Loads (C_{EQCR})	1.6
Dedicated Clock Buffer Loads (C_{EQCD})	0.7
I/O Clock Buffer Loads (C_{EQCI})	0.9

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. EQ 5 shows a piece-wise linear summation over all components.

$$\begin{aligned}
\text{Power} = {} & VCC^2 * [(m * C_{EQM} * f_m)_{modules} + (n * C_{EQI} * f_n)_{inputs} \\
& + (p * (C_{EQO} + C_L) * fp)outputs \\
& + 0.5 * (q1 * C_{EQCR} * f_{q1})_{routed_Clk1} + (r1 * fq1)_{routed_Clk1} \\
& + 0.5 * (q2 * C_{EQCR} * fq2)_{routed_Clk2} \\
& + (r_2 * f_{q2})_{routed_Clk2} + 0.5 * (s_1 * C_{EQCD} * f_{s1})_{dedicated_Clk} \\
& + (s_2 * C_{EQCI} * f_{s2})_{IO_Clk}]
\end{aligned}$$

EQ 5

Where:

m = Number of logic modules switching at f_m

n = Number of input buffers switching at f_n

p = Number of output buffers switching at f_p

q1 = Number of clock loads on the first routed array clock

q2 = Number of clock loads on the second routed array clock

r_1 = Fixed capacitance due to first routed array clock

r_2 = Fixed capacitance due to second routed array clock

s_1 = Fixed number of clock loads on the dedicated array clock

s_2 = Fixed number of clock loads on the dedicated I/O clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_{EQCD} = Equivalent capacitance of dedicated array clock in pF

C_{EQCI} = Equivalent capacitance of dedicated I/O clock in pF

C_L = Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

f_{q2} = Average second routed array clock rate in MHz

f_{s1} = Average dedicated array clock rate in MHz

f_{s2} = Average dedicated I/O clock rate in MHz

Table 2-11 • **Fixed Capacitance Values for Microsemi FPGAs**

Device Type	r1, routed_Clk1	r2, routed_Clk2
A1415A	60	60
A14V15A	57	57
A1425A	75	75
A14V25A	72	72
A1440A	105	105
A14V40A	100	100
A1440B	105	105
A1460A	165	165
A14V60A	157	157
A1460B	165	165
A14100A	195	195
A14V100A	185	185
A14100B	195	195

Table 2-12 • **Fixed Clock Loads (s1/s2)**

Device Type	s1, Clock Loads on Dedicated Array Clock	s2, Clock Loads on Dedicated I/O Clock
A1415A	104	80
A14V15A	104	80
A1425A	160	100
A14V25A	160	100
A1440A	288	140
A14V40A	288	140
A1440B	288	140
A1460A	432	168
A14V60A	432	168
A1460B	432	168
A14100A	697	228
A14V100A	697	228
A14100B	697	228

Timing Derating

ACT 3 devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

***Table 2-15* • Timing Derating Factor (Temperature and Voltage)**

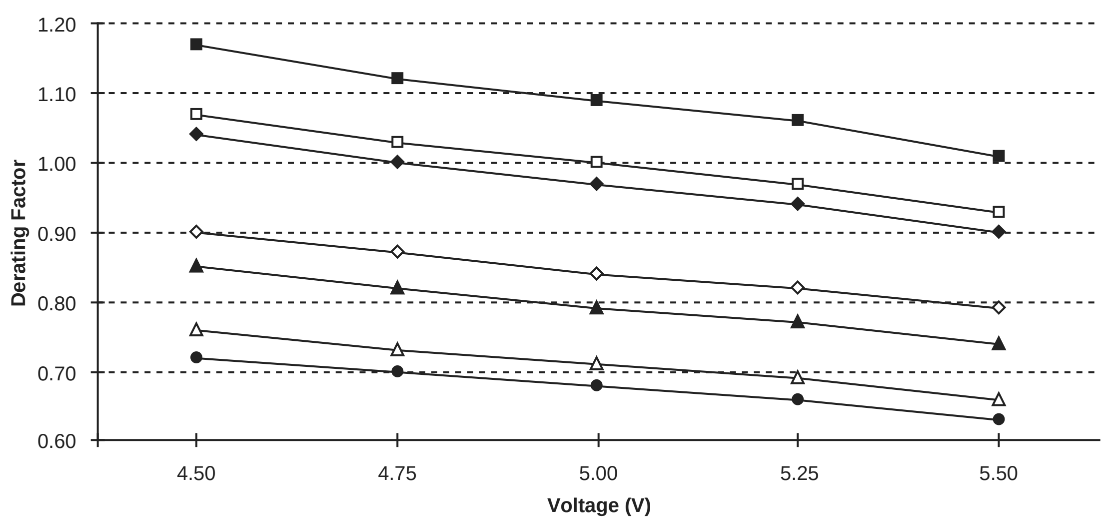
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	**Max.**	**Min.**	Max.
	0.66	1.07	0.63	1.17

***Table 2-16* • Timing Derating Factor for Designs at Typical Temperature (T_J = 25°C) and Voltage (5.0 V)**

(Commercial Maximum Specification) x	0.85

***Table 2-17* • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)**

	–55	**–40**	**0**	**25**	**70**	**85**	**125**
4.50	0.72	0.76	0.85	0.90	1.04	1.07	1.117
4.75	0.70	0.73	0.82	0.87	1.00	1.03	1.12
5.00	0.68	0.71	0.79	0.84	0.97	1.00	1.09
5.25	0.66	0.69	0.77	0.82	0.94	0.97	1.06
5.50	0.63	0.66	0.74	0.79	0.90	0.93	1.01



Note: This derating factor applies to all routing and propagation delays.

***Figure 2-18* • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)**

A1425A, A14V25A Timing Characteristics

Table 2-22 **• A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C[1]**

Logic Module Propagation Delays[2]		–3 Speed[3]		–2 Speed[3]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t_{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t_{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays[4]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t_{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t_{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t_{WCLKA}	Flip-Flop Clock Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t_A	Flip-Flop Clock Input Period	4.0		5.0		6.8		8.0		10.0		ns
f_{MAX}	Flip-Flop Clock Frequency		250		200		150		125		100	MHz

Notes:

1. *VCC = 3.0 V for 3.3 V specifications.*
2. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.*
3. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
4. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A1440A, A14V40A Timing Characteristics (continued)

***Table 2-29* • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

Dedicated (hardwired) I/O Clock Network		–3 Speed[1]		–2 Speed[1]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{IOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t_{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t_{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t_{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t_{IOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t_{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f_{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t_{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t_{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t_{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t_{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t_{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t_{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f_{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t_{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t_{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t_{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t_{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t_{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f_{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
$t_{IOHCKSW}$	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
$t_{IORCKSW}$	I/O Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	3.0 3.0	ns
t_{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	ns

Notes:

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Delays based on 35 pF loading.*

SDO Serial Data Output (Output)

Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

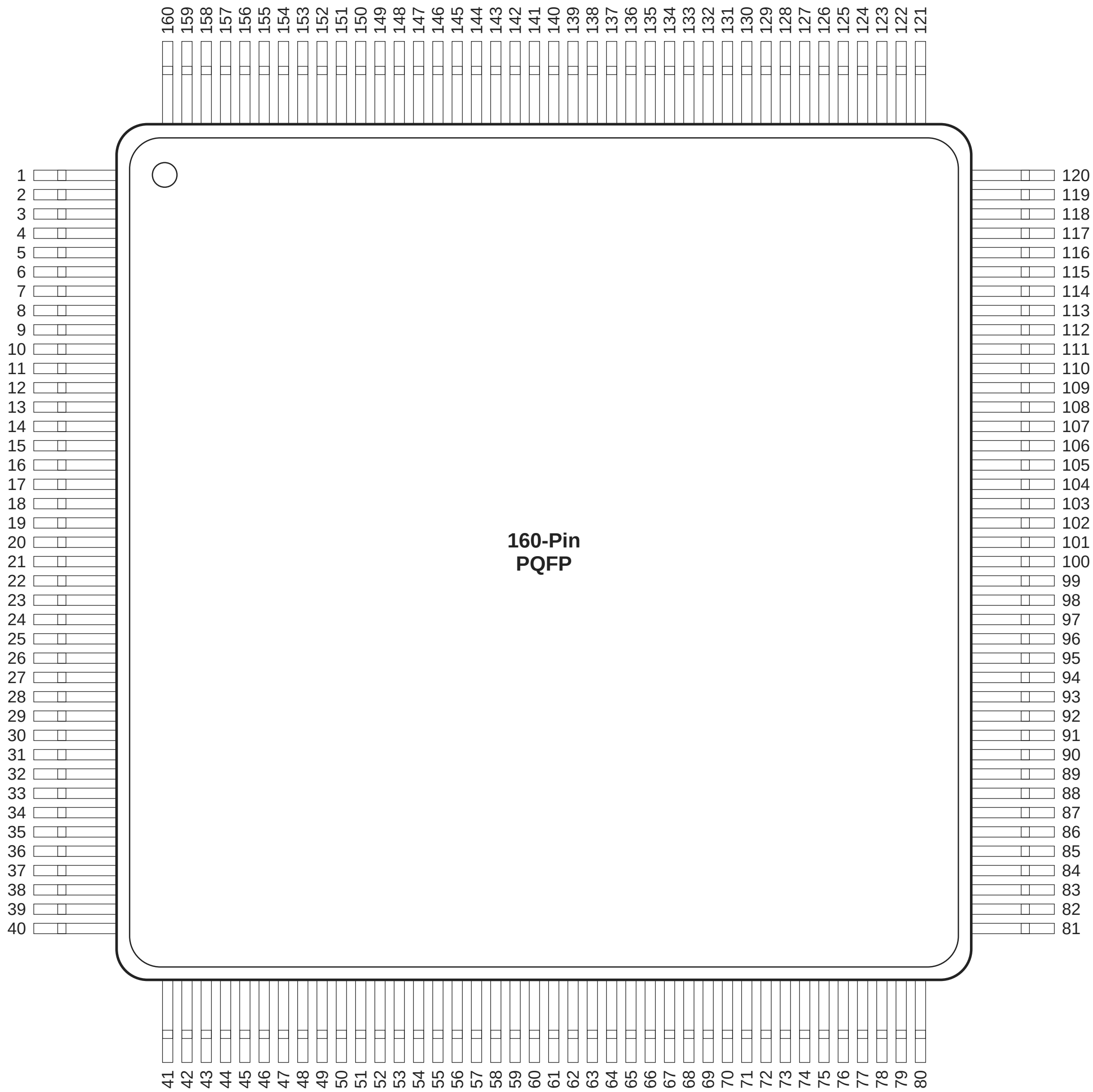
DCLK Diagnostic Clock (Input)

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

VCC 5 V Supply Voltage

HIGH supply voltage.

PQ160



Note: This is the top view of the package

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

TQ176		
Pin Number	A1440, A14V40 Function	A1460, A14V60 Function
1	GND	GND
2	SDI, I/O	SDI, I/O
10	MODE	MODE
11	VCC	VCC
20	NC	I/O
21	GND	GND
22	VCC	VCC
23	GND	GND
32	VCC	VCC
33	VCC	VCC
44	GND	GND
49	NC	I/O
51	NC	I/O
63	NC	I/O
64	PRB, I/O	PRB, I/O
65	GND	GND
66	VCC	VCC
67	VCC	VCC
69	HCLK, I/O	HCLK, I/O
82	NC	I/O
83	NC	I/O
87	SDO	SDO
88	IOPCL, I/O	IOPCL, I/O

TQ176		
Pin Number	A1440, A14V40 Function	A1460, A14V60 Function
89	GND	GND
98	VCC	VCC
99	VCC	VCC
108	GND	GND
109	VCC	VCC
110	GND	GND
119	NC	I/O
121	NC	I/O
122	VCC	VCC
123	GND	GND
124	VCC	VCC
132	IOCLK, I/O	IOCLK, I/O
133	GND	GND
138	NC	I/O
152	CLKA, I/O	CLKA, I/O
153	CLKB, I/O	CLKB, I/O
154	VCC	VCC
155	GND	GND
156	VCC	VCC
157	PRA, I/O	PRA, I/O
158	NC	I/O
170	NC	I/O
176	DCLK, I/O	DCLK, I/O

Notes:

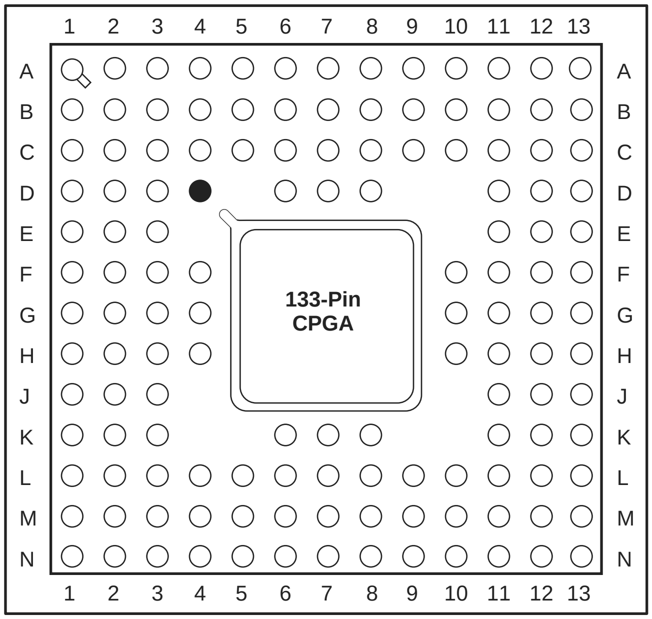
1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG100	
A1415 Function	**Location**
CLKA or I/O	C7
CLKB or I/O	D6
DCLK or I/O	C4
GND	C3, C6, C9, E9, F3, F9, J3, J6, J8, J9
HCLK or I/O	H6
IOCLK or I/O	C10
IOPCL or I/O	K9
MODE	C2
PRA or I/O	A6
PRB or I/O	L3
SDI or I/O	B3
SDO	L9
VCC	B6, B10, E11, F2, F10, G2, K2, K6, K10

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG100 package has been discontinued.

PG133



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

PG175	
A1440 Function	**Location**
CLKA or I/O	C9
CLKB or I/O	A9
DCLK or I/O	D5
GND	D4, D8, D11, D12, E4, E14, H4, H12, L4, L12, M4, M8, M12
HCLK or I/O	R8
IOCLK or I/O	E12
IOPCL or I/O	P13
MODE	F3
NC	A1, A2, A15, B2, B3, P2, P14, R1, R2, R14, R15
PRA or I/O	B8
PRB or I/O	R7
SDI or I/O	D3
SDO	N12
VCC	C3, C8, C13, E15, H3, H13, L1, L14, N3, N8, N13

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG175 package has been discontinued.

4 – Datasheet Information

List of Changes

The following table lists critical changes that were made in each version of the datasheet.

Revision	Changes	Page
Revision 3 (January 2012)	The description for SDO pins had earlier been removed from the datasheet and has now been included again, in the "Pin Descriptions" section (SAR 35820).	2-21
	SDO pin numbers had earlier been removed from package pin assignment tables in the datasheet, and have now been restored to the pin tables (SAR 35820).	3-1
Revision 2 (September 2011)	The ACT 3 datasheet was formatted newly in the style used for current datasheets. The same information is present (other than noted in the list of changes for this revision) but divided into chapters.	N/A
	The datasheet was revised to note in multiple places that speed grades –2 and –3 have been discontinued. The following device/package combinations have been discontinued for all speed grades and temperatures (SAR 33872): A1415 PG100 A1425 PG133 A1440 PG175 A1460 BG225 Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004.	I and others
	The "Features" section was revised to state the clock-to-ouput time and on-chip performance for –1 speed grade as 9.0 ns and 186 MHz. The "General Description" section was revised in accordance (SAR 33872).	I
	The maximum performance values were updated in Table 1 • ACT 3 Family Product Information, and now reflect worst-case commercial for the –1 speed grade (SAR 33872).	I
	The "Product Plan" table was updated as follows to conform to current offerings (SAR 33872): The A1415A device is offered in PL84, PG100, and VQ100 packages for Military application. The A1440A device is offered in TQ176 and VQ100 packages for Industrial application.	III
	Table 1-1 • Chip-to-Chip Performance (worst-case commercial) was updated to include data for all speed grades instead of only –3 (SAR 33872).	1-2
	Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade) was revised to reflect values for the –1 speed grade (SAR 33872).	1-1
	Figure 2-10 • Timing Model was updated to show data for the –1 speed grade instead of –3 (SAR 33872).	2-16
	Table 2-14 • Logic Module and Routing Delay by Fanout (ns); Worst-Case Commercial Conditions was updated to include data for all speed grades instead of only –3 (SAR 33872).	2-20
	Package names used in the "Package Pin Assignments" section and throughout the document were revised to match standards given in *Package Mechanical Drawings* (SAR 27395).	3-1

Revision	Changes	Page
Revision 2 (continued)	In the "Package Pin Assignments" section, notes were added to the pin tables for the following packages, stating that they are discontinued: "BG225" "PG100" "PG133" "PG175"	 3-20 3-24 3-26 3-28
Revision 1 (June 2006)	RoHS compliant information was added to the "Ordering Information" section.	II

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